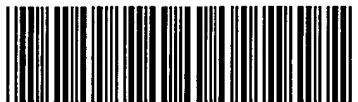


Search Notes**Application/Control No.**

09/766,270

Examiner

Chau Nguyen

Applicant(s)/Patent under Reexamination

SEKIDO ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	522-523	9/28/2004	CN
715	530	9/28/2004	CN
715	531	9/29/2004	CN
715	539	9/29/2004	CN
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Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	09/28/2004	CN
	9/29/2004	CN
	10/4/2004	CN
	10/12/2004	CN
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NPL Search on IEEE Database	11/23/2005	CN